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SHEET 1 OF 1

Form PTO 1449 (Modified)				218264US3		SERIAL	10/051,042	
LIST OF	REFER	RENCES CITED BY APPLI		APPLICANT Eiichi SANO, et al.				
			FILING DATE		GROUP			
				January 22, 2002		<u> </u>	1712 111	
U.S. PATENT DOCUMENTS								
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FOREIGN PATENT DOCUMENTS								
		DOCUMENT NUMBER	DATE	COUNTRY		YE	TRANSLATION YES NO	
El,	AO	0 288 257	10/26/88	EUROPE				
El	ΑP	11-188828		JAPAN (with English Abstract			X	
GC.	AQ	0 868 999		EUROPE				
70	AR	0 678 607		EUROPE				
	AS	WO 99/54134	10/28/99	WIPO				
	AT							
	AU							
	AV							
OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)								
	AW							
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	AY							
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